Session 3E

Opportunities with the Open Architecture Test System

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To contain the exponentially increasing test equipment cost, an initiative to develop Open Architecture Tester has gained tremendous momentum. A large number of companies worldwide are participating with Semiconductor Test Consortium (STC) for the development of Open Architecture Test System. The basic philosophy behind the Open Architecture Test System is reconfigurable system with use of third party modules in a plug-and-play manner. In this panel, tester vendors, IC manufacturers, module vendors, STC representatives will present their views.

**Firing Line** A panel should not be limited to the views presented by the panelists. Hence, a small group of well known researchers has been formed as a firing line. These are designated persons to ask questions, including on the subject and opinion that differ from the panelists views.

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